

7. MEASUREMENT OF INTENSITIES

7.4.4

- Brown, G. S. & Lindau, I. (1986). Editors, *Synchrotron radiation instrumentation*. Proceedings of the International Conference on X-ray and VUV Synchrotron Radiation Instrumentation. *Nucl. Instrum. Methods*, **A246**, 511–595.
- Mathieson, A. McL. (1985). *Small-crystal X-ray diffractometry with a crystal ante-monochromator*. *Acta Cryst.* **A41**, 309–316.
- Matsushita, T. & Hashizume, H. (1983). *Handbook of synchrotron radiation*, Vol. I, edited by E. E. Koch, pp. 261–314. Amsterdam: North-Holland.
- Matsushita, T. & Kaminaga, U. (1980). *A systematic method of estimating the performance of X-ray optical systems for synchrotron radiation. I. Description of various optical elements in position-angle space for ideally monochromatic X-rays*. *J. Appl. Cryst.* **13**, 465–471; *II. Treatment in position-angle-wavelength space*. *J. Appl. Cryst.* **13**, 472–478.
- Suortti, P. (1980). *Components of the total X-ray scattering. Accuracy in powder diffraction*, edited by S. Block & C. R. Hubbard, pp. 1–20. *Natl. Bur. Stand. (US) Spec. Publ.* No. 567.
- Suortti, P. (1985). *Parallel beam geometry for single-crystal diffraction*. *J. Appl. Cryst.* **18**, 272–274.
- Suortti, P., Hastings, J. B. & Cox, D. E. (1985). *Powder diffraction with synchrotron radiation. I. Absolute measurements*. *Acta Cryst.* **A41**, 413–416.
- Suortti, P. & Jennings, L. D. (1977). *Accuracy of structure factors from X-ray powder intensity measurements*. *Acta Cryst.* **A33**, 1012–1027.
- Thomlinson, W. & Williams, G. P. (1984). Editors. *Synchrotron radiation instrumentation 3*. Proceedings of the Third National Conference on Synchrotron Radiation Instrumentation. *Nucl. Instrum. Methods*, **222**, 215–278.
- Killean, R. C. G. (1973). *Optimization of scan procedure for single-crystal X-ray diffraction intensities*. *Acta Cryst.* **A29**, 216–217.
- Mack, M. & Spielberg, N. (1958). *Statistical factors in X-ray intensity measurements*. *Spectrochim. Acta*, **12**, 169–178.
- Mackenzie, J. K. & Williams, E. J. (1973). *The optimum distribution of counting times for determining integrated intensities with a diffractometer*. *Acta Cryst.* **A29**, 201–204.
- Olkha, G. S. & Rathie, P. N. (1971). *On a generalized Bessel function and an integral transform*. *Math. Nachr.* **51**, 231–240.
- Paciorek, W. A. & Chapuis, G. (1994). *Generalized Bessel functions in incommensurate structure analysis*. *Acta Cryst.* **A50**, 194–203.
- Parrish, W. (1956). *X-ray intensity measurements with counter tubes*. *Philips Tech. Rev.* **17**, 206–221.
- Prince, E. & Nicholson, W. L. (1985). *The influence of individual reflections on the precision of parameter estimates in least squares refinement*. *Structure & statistics in crystallography*, edited by A. J. C. Wilson, pp. 183–195. Guildersland, NY: Adenine Press.
- Shmueli, U. (1993). Editor. *International tables for crystallography*. Vol. B. *Reciprocal space*. Dordrecht: Kluwer.
- Shoemaker, D. P. (1968). *Optimization of counting times in computer-controlled X-ray and neutron single-crystal diffractometry*. *Acta Cryst.* **A24**, 136–142.
- Shoemaker, D. P. & Hamilton, W. C. (1972). *Further remarks concerning optimization of counting times in single-crystal diffractometry: rebuttal to Killean; consideration of background counting and slewing times*. *Acta Cryst.* **A28**, 408–411.
- Skellam, J. G. (1946). *The frequency distribution of the difference between two Poisson values belonging to different populations*. *J. R. Stat. Soc.* **109**, 296.
- Szabó, P. (1978). *Optimization of the measuring time in diffraction intensity measurements*. *Acta Cryst.* **A34**, 551–553.
- Thomsen, J. S. & Yap, F. Y. (1968). *Simplified method of computing centroids of X-ray profiles*. *Acta Cryst.* **A24**, 702–703.
- Werner, S. A. (1972a). *Choice of scans in X-ray diffraction*. *Acta Cryst.* **A28**, 143–151.
- Werner, S. A. (1972b). *Choice of scans in neutron diffraction*. *Acta Cryst.* **A28**, 665–669.
- Wilson, A. J. C. (1967). *Statistical variance of line-profile parameters. Measures of intensity, location and dispersion*. *Acta Cryst.* **23**, 888–898.
- Wilson, A. J. C. (1978). *On the probability of measuring the intensity of a reflection as negative*. *Acta Cryst.* **A34**, 474–475.
- Wilson, A. J. C. (1980). *Relationship between 'observed' and 'true' intensity: effect of various counting modes*. *Acta Cryst.* **A36**, 929–936.
- Wilson, A. J. C., Thomsen, J. S. & Yap, F. Y. (1965). *Minimization of the variance of parameters derived from X-ray powder diffractometer line profiles*. *Appl. Phys. Lett.* **7**, 163–165.
- Wright, E. M. (1933). *On the coefficients of power series having exponential singularities*. *J. London Math. Soc.* **8**, 71–79.
- Zevin, L. S., Umanskii, M. M., Kheiker, D. M. & Panchenko, Yu. M. (1961). *K voprosu o diffraktoметрических priemah pretsizionnyh izmerenii elementarnykh yacheek*. *Kristallografiya*, **6**, 348–356.

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- Abramowitz, M. & Stegun, I. A. (1964). *Handbook of mathematical functions*. National Bureau of Standards Publication AMS 55.
- Boer, J. L. de (1982). *Statistics of recorded counts*. *Crystallographic statistics*, edited by S. Ramaseshan, M. F. Richardson & A. J. C. Wilson, pp. 179–186. Bangalore: Indian Academy of Sciences.
- Estabrook, J. N. & Hughes, J. W. (1953). *Elimination of dead-time corrections in monitored Geiger-counter X-ray measurements*. *J. Sci. Instrum.* **30**, 317–320.
- French, S. & Wilson, K. (1978). *On the treatment of negative intensity observations*. *Acta Cryst.* **A34**, 517–525.
- Grant, D. F. (1973). *Single-crystal diffractometer data: the on-line control of the precision of intensity measurement*. *Acta Cryst.* **A29**, 217.
- Hirshfeld, F. L. & Rabinovich, D. (1973). *Treating weak reflexions in least-squares calculations*. *Acta Cryst.* **A29**, 510–513.
- Killean, R. C. G. (1967). *A note on the a priori estimation of R factors for constant-count-per-reflection diffractometer experiments*. *Acta Cryst.* **23**, 1109–1110.
- Killean, R. C. G. (1972). *The a priori optimization of diffractometer data to achieve the minimum average variance in the electron density*. *Acta Cryst.* **A28**, 657–658.